TTTC News

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PAST TTTC EVENTS

The 23rd Design, Automation, and Test in Europe (DATE) Conference
March 9–13, 2020
Grenoble, France
https://www.date-conference.com/

The 23rd DATE conference and exhibition is the main European event bringing together designers and design automation users, researchers, and vendors, as well as specialists in the hardware and software design, test, and manufacturing of electronic circuits and systems. DATE puts a strong emphasis on both technology and systems, covering ICs/ SoCs, reconfigurable hardware and embedded systems, and embedded software.

The five-day event consists of a conference with plenary invited papers, regular papers, panels, hot-topic sessions, tutorials and workshops, two special focus days, and a track for executives. The scientific conference is complemented by a commercial exhibition displaying the state of the art in design and test tools, methodologies, IP and design services, reconfigurable and other hardware platforms, embedded software, and (industrial) design experiences from different application domains, for example, automotive, the Internet of Things (IoT), wireless, telecom, and multimedia applications. The organization of user group meetings, fringe meetings, a university booth, a PhD forum, vendor presentations, and social events offers a wide variety of extra opportunities to meet and exchange information on relevant issues for the design and test community. Special space will also be allocated for EU-funded projects to show their results.

The IEEE VLSI Test Symposium
April 5–8, 2020
San Diego, CA, USA
http://tttc-vts.org/public_html/new/2020/

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in testing, debug, and repair of microelectronic circuits and systems.

The VTS Program Committee invites original, unpublished paper submissions for VTS 2020. Proposals for the innovative practices and special sessions tracks are also invited. Paper submissions should be complete manuscripts, up to six pages (inclusive of figures, tables, and bibliography) in a standard IEEE two-column format; papers exceeding the page limit will be returned without review. Authors should clearly explain the significance of the work, highlight novel features, and describe its current status. On the title page, please include author name(s) and affiliation(s), and the mailing address, phone number, and e-mail address of the contact author. A 50-word abstract and five keywords identifying the topic area are also required.

VTS 2020 will present a Best Paper Award, a Best Special Session Award, and a Best Innovative Practices Session Award based on the evaluations of reviewers, attendees, and an invited panel of judges. We also plan to organize various student activities including the TTTC Best Doctoral Thesis Contest, details of which will be made available through the website.

The 25th IEEE European Test Symposium (ETS'20)
May 25–29, 2020
Tallinn, Estonia
http://ets2020.taltech.ee/

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of

electronic-based circuits and system testing, reliability, security, and validation.

In 2020, ETS will take place in the Radisson Blu Sky Hotel in Tallinn. The city is known for the picturesque old town with its medieval architecture. It is organized by the Tallinn University of Technology (TalTech), which cosponsors the event jointly with the IEEE Council on Electronic Design Automation (CEDA). In addition to scientific paper submissions, ETS offers a track for informal contributions dedicated to early hot ideas and relevant case studies as well as a PhD forum. A Test Spring School and Fringe Workshops will be organized in conjunction with ETS'20.

The 26th International Symposium on On-Line Testing and Robust System Design (IOLTS'20)
July 13–15, 2020
Naples, Italy
http://tima.univ-grenoble-alpes.fr/conferences/iolts/iolts20/

The International Symposium on On-Line Testing and Robust System Design (IOLTS) is an established forum for presenting novel ideas and experimental data on these areas. The symposium is sponsored by the IEEE CEDA and the 2020 edition is organized by the IEEE Computer Society Test Technology Technical Council, the Politecnico di Torino, the University of Athens, the TIMA Laboratory, and iRoC Technologies.

Issues related to online testing techniques, and more generally to design for robustness, are increasingly important in modern electronic systems. In particular, the huge complexity of electronic systems has led to growth in reliability needs in several application domains as well as pressure for low cost products. There is a corresponding increase in demand for cost-effective design for robustness techniques. These needs have increased dramatically with the introduction of nanometer technologies, which impact adversely noise margins; process, voltage, and temperature variations; aging and wear-out; soft error and EMI sensitivity; power density and heating; and make mandatory the use of design for robustness techniques for extending, yield, reliability, and lifetime of modern SoCs. Design for reliability also becomes mandatory for reducing power dissipation, as voltage reduction, often used to reduce power, strongly affects reliability by reducing noise margins and thus the sensitivity to soft-errors and EMI, and by increasing circuit delays and thus the severity of timing faults. There is also a strong relation between design for reliability and design for security, as security attacks are often fault-based.

NEWSLETTER EDITOR'S INVITATION

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia 1678, Cyprus; ttheocharides@ucy.ac.cy.

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CONTRIBUTIONS TO THIS NEWSLETTER: Send contributions to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia 1678, Cyprus; ttheocharides@ucy.ac.cy. For more information, see the TTTC Web page: http://tab.computer.org/tttc.